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FCC TEST REPORT

Product: Thermal Receipt Printer

Trade mark : Rongta

Model/Type reference : RP80-WUS, RP850-WUS,

RP820-WUS, RP804-WUS

Serial Number : N/A

Report Number : EED32l00065501 FCCID : 2AD6G-RP80-WUS

Date of Issue : Sep. 22, 2016

Test Standards : 47 CFR Part 15 Subpart B (2015)

Test result : PASS

Prepared for:

XIAMEN RONGTA TECHNOLOGY CO., LTD.

3F-1/E Building, No.195 Gaoqishe, Gaodian Village, Dianqian Street
Office, Huli District, Xiamen City

Prepared by:

Centre Testing International Group Co., Ltd. Hongwei Industrial Zone, Bao'an 70 District, Shenzhen, Guangdong, China

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Reviewed by Report Seal Date:

Tom-chen

Compiled by:

Approved by:

Kevin yang (Project Engineer)

Tom chen (Test Project)

Kevin lan (Reviewer)

Sep. 22, 2016

Sheek Luo (Lab supervisor)

Check No.: 2392104606





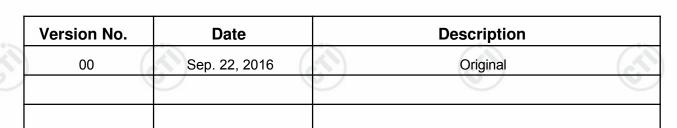




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2 Version











































































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3 Test Summary

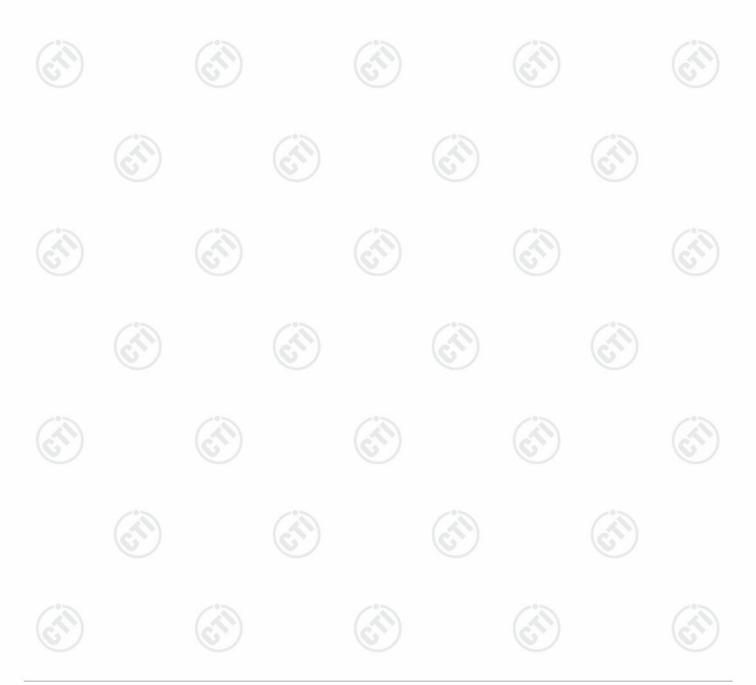
Test Item	Test Requirement	Test method	Result
Radiated Emission	47 CFR Part 15B	ANSI C63.4-2014	PASS
Conducted Emission (150KHz to 30MHz)	47 CFR Part 15B	ANSI C63.4-2014	PASS

Remark:

The tested samples and the sample information are provided by the client.

Model No.: RP80-WUS, RP850-WUS, RP820-WUS, RP804-WUS

Only the model RP80-WUS was tested, since the electrical circuit design, layout, components used and internal wiring were identical for the above models, with difference being the shell structure of the whole machine.











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5 General Information

5.1 Client Information

Applicant:	XIAMEN RONGTA TECHNOLOGY CO., LTD.
Address of Applicant:	3F-1/E Building, No.195 Gaoqishe, Gaodian Village, Dianqian Street Office, Huli District, Xiamen City
Manufacturer:	XIAMEN RONGTA TECHNOLOGY CO., LTD.
Address of Manufacturer:	3F-1/E Building, No.195 Gaoqishe, Gaodian Village, Dianqian Street Office, Huli District, Xiamen City
Factory:	XIAMEN RONGTA TECHNOLOGY CO., LTD.
Address of Factory:	3F-1/E Building, No.195 Gaoqishe, Gaodian Village, Dianqian Street Office, Huli District, Xiamen City

5.2 General Description of EUT

Product Name:	Thermal Receipt Printer					
Model No.(EUT):	RP80-WUS, RP850-WUS, RP820-WUS, RP804-WUS					
Test Model No.: RP80-WUS						
Trade Mark:	Rongta					
EUT Supports Radios application	Wlan 2.4GHz 802.11b/g/n(HT20&HT40)					
AC adapter:	AC 100-240V, 50/60Hz, 1.5A Output: DC 24V, 2.5A					

5.3 Product Specification subjective to this standard

Test Power Grade:	02.11b:14, 802.11g: 10, 802.11n(HT20): 0B, 802.11n(HT40): 0B manufacturer declare)					
Test Software of EUT:	RT5350QA (manufacturer declare)					
Test Voltage:	AC 120V, 60Hz					
Sample Received Date:	Apr. 08, 2016	(i)				
Sample tested Date:	Apr. 08, 2016 to Sep. 20, 2016	5)				

5.4 Test Environment and Mode

Operating Environmen	nt:			
Temperature:	24°C			(2)
Humidity:	50% RH			
Atmospheric Pressure:	1010mbar			
Test mode:				
Normal operation:	Keep the EUT	at normal operation r	node.	
10.0	10.0	163	160	





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5.5 Description of Support Units

The EUT has been tested with associated equipment below.

Associated (Associated equipment name		Model	Supplied by	
AE1	Notebook	DELL	V3400D-326	CTI	
AE2	Mouse	L.Selectron	M004	СТІ	
AE3	3 Notebook		E46L	CTI	
AE4	Mouse	L.Selectron	OP-200	CTI	

5.6 Test Location

All tests were performed at:

Centre Testing International Group Co., Ltd.

Hongwei Industrial Zone, Bao'an 70 District, Shenzhen, Guangdong, China 518101

Telephone: +86 (0) 755 3368 3668 Fax:+86 (0) 755 3368 3385

No tests were sub-contracted.

5.7 Test Facility

The test facility is recognized, certified, or accredited by the following organizations:

CNAS-Lab Code: L1910

Centre Testing International Group Co., Ltd. has been assessed and proved to be in compliance with CNAS-CL01 Accreditation Criteria for Testing and Calibration Laboratories (identical to ISO/IEC 17025: 2005 General Requirements) for the Competence of Testing and Calibration Laboratories..

A2LA-Lab Cert. No. 3061.01

Centre Testing International Group Co., Ltd. EMC Laboratory has been accredited by A2LA for technical competence in the field of electrical testing, and proved to be in compliance with ISO/IEC 17025: 2005 General Requirements for the Competence of Testing and Calibration Laboratories and any additional program requirements in the identified field of testing.

FCC-Registration No.: 886427

Centre Testing International Group Co., Ltd. EMC Laboratory has been registered and fully described in a report filed with the FCC (Federal Communications Commission). The acceptance letter from the FCC is maintained in our files. Registration 886427.

IC-Registration No.: 7408A-2

The 3m Alternate Test Site of Centre Testing International Group Co., Ltd. has been registered by Certification and Engineering Bureau of Industry Canada for the performance of radiated measurements with Registration No. 7408A-2.

IC-Registration No.: 7408B-1

The 10m Alternate Test Site of Centre Testing International Group Co., Ltd. has been registered by Certification and Engineering Bureau of Industry Canada for the performance of radiated measurements with Registration No. 7408B-1.

NEMKO-Aut. No.: ELA503



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Centre Testing International Group Co., Ltd. has been assessed the quality assurance system, the testing facilities, qualifications and testing practices of the relevant parts of the organization. The quality assurance system of the Laboratory has been validated against ISO/IEC 17025 or equivalent. The laboratory also fulfils the conditions described in Nemko Document NLA-10.

VCCI

The Radiation 3 &10 meters site of Centre Testing International Group Co., Ltd. has been registered in accordance with the Regulations for Voluntary Control Measures with Registration No.: R-4096. Main Ports Conducted Interference Measurement of Centre Testing International Group Co., Ltd. has been registered in accordance with the Regulations for Voluntary Control Measures with Registration No.: C-4563.

Telecommunication Ports Conducted Disturbance Measurement of Centre Testing International Group Co., Ltd. has been registered in accordance with the Regulations for Voluntary Control Measures with Registration No.: T-2146.

The Radiation 3 meters site of Centre Testing International Group Co., Ltd. has been registered in accordance with the Regulations for Voluntary Control Measures with Registration No.: G-758

5.8 Deviation from Standards

None.

5.9 Abnormalities from Standard Conditions

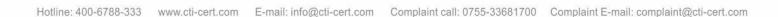
None.

5.10 Other Information Requested by the Customer

None.

5.11 Measurement Uncertainty (95% confidence levels, k=2)

No.	ltem	Measurement Uncertainty					
21/	Radio Frequency	7.9 x 10 ⁻⁸					
2	Dedicted Courieus emission	4.5dB (30MHz-1GHz)					
2	Radiated Spurious emission	4.8dB (1GHz-12.75GHz)					
2	Conduction emission	3.6dB (9kHz to 150kHz)					
3	Conduction emission	3.2dB (150kHz to 30MHz)					
4	Temperature	0.64°C					
5	Humidity	2.8%					
6	DC power voltages	0.025%					











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6 Equipment List

Conducted disturbance Test										
Equipment	Manufacturer	Model No.	Serial Number	Cal. date (mm-dd-yyyy)	Cal. Due date (mm-dd-yyyy)					
Receiver	R&S	ESCI	100009	06-16-2016	06-15-2017					
Temperature/ Humidity Indicator	TAYLOR	1451	1905	04-27-2016	04-26-2017					
LISN	R&S	ENV216	100098	06-16-2016	06-15-2017					
LISN	schwarzbeck	NNLK8121	8121-529	06-16-2016	06-15-2017					
Voltage Probe	R&S	ESH2-Z3	(C)	07-09-2014	07-07-2017					
Current Probe	R&S	R&S EZ17		06-16-2016	06-15-2017					
ISN	TESEQ GmbH	ISN T800	30297	01-29-2015	01-27-2017					



























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	3M	Semi/full-anech	oic Chamber			
Equipment	Manufacturer Model No.		Serial Number	Cal. date (mm-dd-yyyy)	Cal. Due date (mm-dd-yyyy)	
3M Chamber & Accessory Equipment	TDK	SAC-3		06-05-2016	06-05-2019	
TRILOG Broadband Antenna	SCHWARZBECK	VULB9163	9163-617	05-23-2016	05-22-2017	
Microwave Preamplifier	Agilent	8449B	3008A02425	02-04-2016	02-03-2017	
Horn Antenna	ETS-LINDGREN	3117	00057407	07-20-2015	07-18-2018	
Loop Antenna	ETS	6502	00071730	07-30-2015	07-28-2017	
Spectrum Analyzer	R&S	FSP40	100416	06-16-2016	06-15-2017	
Receiver	R&S	ESCI	100435	06-16-2016	06-15-2017	
Multi device Controller	maturo	NCD/070/10711 112		01-12-2016	01-11-2017	
LISN	schwarzbeck	NNBM8125	81251547	06-16-2016	06-15-2017	
LISN	schwarzbeck	NNBM8125	81251548	06-16-2016	06-15-2017	
Signal Generator	Agilent	E4438C	MY45095744	04-01-2016	03-31-2017	
Signal Generator	Keysight	E8257D	MY53401106	04-01-2016	03-31-2017	
Temperature/ Humidity Indicator	TAYLOR	1451	1905	04-27-2016	04-26-2017	
Cable line	Fulai(7M)	SF106	5219/6A	01-12-2016	01-11-2017	
Cable line	Fulai(6M)	SF106	5220/6A	01-12-2016	01-11-2017	
Cable line	Fulai(3M)	SF106	5216/6A	01-12-2016	01-11-2017	
Cable line	Fulai(3M)	SF106	5217/6A	01-12-2016	01-11-2017	
High-pass filter	Sinoscite	FL3CX03WG18 NM12-0398-002		01-12-2016	01-11-2017	
High-pass filter	MICRO- TRONICS	SPA-F-63029-4	(5)	01-12-2016	01-11-2017	
band rejection filter			(7)	01-12-2016	01-11-2017	
band rejection filter				01-12-2016	01-11-2017	
band rejection filter	Sinoscite	FL5CX02CA04C L12-0396-002		01-12-2016	01-11-2017	
band rejection filter	Sinoscite	FL5CX02CA03C L12-0394-001		01-12-2016	01-11-2017	





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7 Test results and Measurement Data

7.1 Conducted Emissions

Test Requirement: 47 CFR Part 15B
Test Method: ANSI C63.4
Test frequency range: 150kHz to 30MHz

Limit:

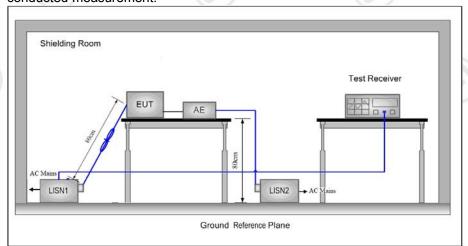
Fraguency range (MHz)	Limit	(dBµV)				
Frequency range (MHz)	Quasi-peak	Average				
0.15-0.5	66 to 56*	56 to 46*				
0.5-5	56	46				
5-30	60	50				

^{*} Decreases with the logarithm of the frequency.

- Test Procedure:

 1) The mains terminal disturbance voltage test was conducted in a shielded room.
 - 2) The EUT was connected to AC power source through a LISN 1 (Line Impedance Stabilization Network) which provides a $50\Omega/50\mu H + 5\Omega$ linear impedance. The power cables of all other units of the EUT were connected to a second LISN 2, which was bonded to the ground reference plane in the same way as the LISN 1 for the unit being measured. A multiple socket outlet strip was used to connect multiple power cables to a single LISN provided the rating of the LISN was not exceeded.
 - 3) The tabletop EUT was placed upon a non-metallic table 0.8m above the ground reference plane. And for floor-standing arrangement, the EUT was placed on the horizontal ground reference plane.
 - 4) The test was performed with a vertical ground reference plane. The rear of the EUT shall be 0.4 m from the vertical ground reference plane. The vertical ground reference plane was bonded to the horizontal ground reference plane. The LISN 1 was placed 0.8 m from the boundary of the unit under test and bonded to a ground reference plane for LISN mounted on top of the ground reference plane. This distance was between the closest points of the LISN 1 and the EUT. All other units of the EUT and associated equipment was at least 0.8 m from the LISN 2.
 - 5) In order to find the maximum emission, the relative positions of equipment and all of the interface cables must be changed according to ANSI C63.4 on conducted measurement.

Test Setup:



Instruments Used:

Refer to section 6 for details

Test Results:

Pass



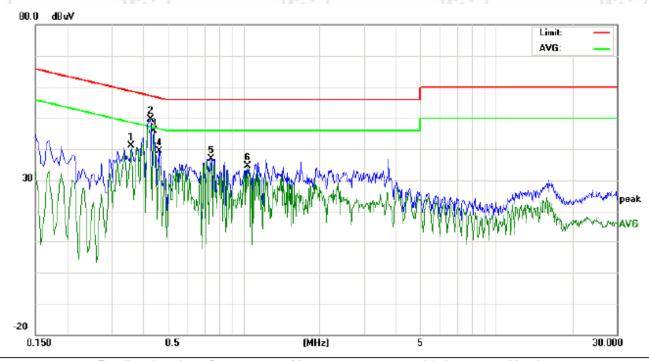
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Measurement Data

An initial pre-scan was performed on the live and neutral lines with peak detector.

Quasi-Peak and Average measurement were performed at the frequencies with maximized peak emission were detected.

Live Line:



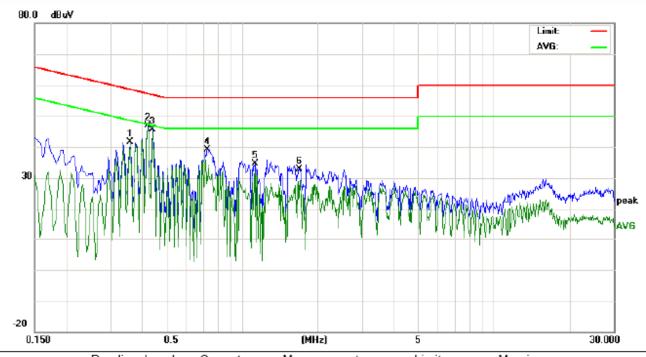
No.	Freq.	Reading_Level (dBuV)			Correct Factor	Measurement (dBuV)			Lir (dB	nit uV)		rgin fB)		
-	MHz	Peak	QP	AVG	dB	peak	QP	AVG	QP	AVG	QP	AVG	P/F	Comment
1	0.3580	31.29	31.12	30.92	9.86	41.15	40.98	40.78	58.77	48.77	-17.79	-7.99	Р	
2	0.4300	39.80	36.20	28.31	9.90	49.70	46.10	38.21	57.25	47.25	-11.15	-9.04	Р	
3	0.4420	36.06	35.14	35.33	9.90	45.96	45.04	45.23	57.02	47.02	-11.98	-1.79	Р	
4	0.4660	29.47	26.54	25.19	9.90	39.37	36.44	35.09	56.58	46.58	-20.14	-11.49	Р	
5	0.7460	26.97	25.90	25.82	9.90	36.87	35.80	35.72	56.00	46.00	-20.20	-10.28	Р	
6	1.0339	24.65	24.12	23.93	10.00	34.65	34.12	33.93	56.00	46.00	-21.88	-12.07	Р	







Neutral Line:



	No.	Freq.	Reading_Level req. (dBuV)		Correct Factor	Measurement (dBuV)			Limit (dBuV)		Margin (dB)				
-		MHz	Peak	QP	AVG	dB	peak	QP	AVG	QP	AVG	QP	AVG	P/F	Comment
3	1	0.3580	31.81	31.40	31.32	9.86	41.67	41.26	41.18	58.77	48.77	-17.51	-7.59	Р	
•	2	0.4220	36.86	38.58	36.18	9.90	46.76	48.48	46.08	57.41	47.41	-8.93	-1.33	Р	
	3	0.4420	33.12	30.10	20.92	9.90	43.02	40.00	30.82	57.02	47.02	-17.02	-16.20	Р	
Ī	4	0.7180	26.95	26.52	25.98	9.90	36.85	36.42	35.88	56.00	46.00	-19.58	-10.12	Р	
	5	1.1260	24.75	23.00	21.90	10.00	34.75	33.00	31.90	56.00	46.00	-23.00	-14.10	Р	
	6	1.7020	22.91	20.17	19.11	10.00	32.91	30.17	29.11	56.00	46.00	-25.83	-16.89	Р	

Notes:

- 1. The following Quasi-Peak and Average measurements were performed on the EUT:
- 2. Final Test Level =Receiver Reading + LISN Factor + Cable Loss.







7.2 Radiated Emission

Test Requirement: 47 CFR Part 15B **Test Method:** ANSI C63.4

Test site: Measurement Distance: 3m (Semi-Anechoic Chamber)

Receiver setup:

Limit:

Frequency	Detector	RBW	VBW	Remark			
30MHz-1GHz	Quasi-peak	120kHz	300kHz	Quasi-peak Value			
Above 1GHz Peak		1MHz	3MHz	Peak Value			
Freque	ency	Limit (dBµV	/m @3m)	Remark			
30MHz-8	8MHz	40.0)	Quasi-peak Value			
88MHz-2	16MHz	43.	5	Quasi-peak Value			
216MHz-9	60MHz	46.0)	Quasi-peak Value			
960MHz-	-1GHz	54.0		Quasi-peak Value			
Above 1	CU-7	54.0		Average Value			
Above	GHZ	74.0)	Peak Value			

Test Procedure:

Below 1GHz test procedure as below:

- a. The EUT was placed on the top of a rotating table 0.8 meters above the ground at a 3 meter semi-anechoic camber. The table was rotated 360 degrees to determine the position of the highest radiation.
- b. The EUT was set 3 meters away from the interference-receiving antenna, which was mounted on the top of a variable-height antenna tower.
- c. The antenna height is varied from one meter to four meters above the ground to determine the maximum value of the field strength. Both horizontal and vertical polarizations of the antenna are set to make the measurement.
- d. For each suspected emission, the EUT was arranged to its worst case and then the antenna was tuned to heights from 1 meter to 4 meters and the rota table table was turned from 0 degrees to 360 degrees to find the maximum reading.
- e. The test-receiver system was set to Peak Detect Function and Specified Bandwidth with Maximum Hold Mode.
- f. If the emission level of the EUT in peak mode was 10dB lower than the limit specified, then testing could be stopped and the peak values of the EUT would be reported. Otherwise the emissions that did not have 10dB margin would be re-tested one by one using peak, quasi-peak or average method as specified and then reported in a data sheet.

Above 1GHz test procedure as below:

- g. Different between above is the test site, change from Semi- Anechoic Chamber to fully Anechoic Chamber (Above 18GHz the distance is 1 meter).
- h. The radiation measurements are performed in X, Y, Z axis positioning for Transmitting mode, and found the X axis positioning which it is worse case.
- i. Repeat above procedures until all frequencies measured was complete.









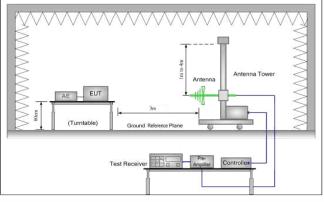




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Test Setup:



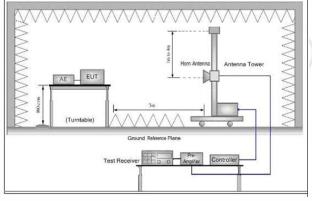


Figure 1. 30MHz to 1GHz

Figure 2. Above 1 GHz

Instruments Used: Refer to section 6 for details

Test Results: Pass











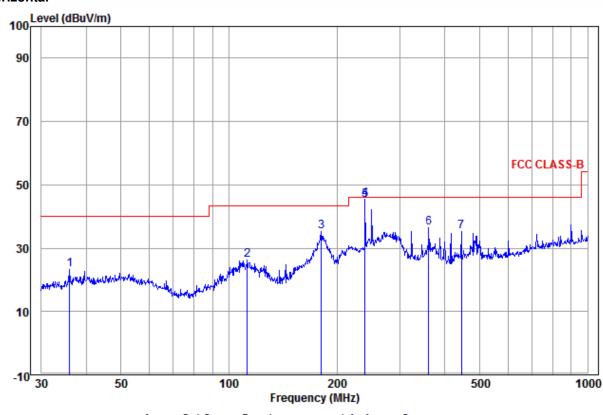




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Below 1GHz Horizontal



		Ant	Capte	Kead		Limit	Over		
	Freq	Factor	Loss	Level	Level	Line	Limit	Pol/Phase	Remark
-	MHz	dB/m	dB	dBuV	dBuV/m	dBuV/m	dB		
1	36.001	13.58	0.77	8.82	23.17	40.00	-16.83	Horizontal	
2	112.524	12.18	1.57	12.37	26.12	43.50	-17.38	Horizontal	
3	181.283	10.95	1.99	22.21	35.15	43.50	-8.35	Horizontal	
4 pp	239.987	12.25	2.32	30.87	45.44	46.00	-0.56	Horizontal	
5 qp		12.25	2.32	30.61	45.18	46.00	-0.82	Horizontal	QP
6								Horizontal	
7	444.851	17.02	2.97	15.23	35.22	46.00	-10.78	Horizontal	















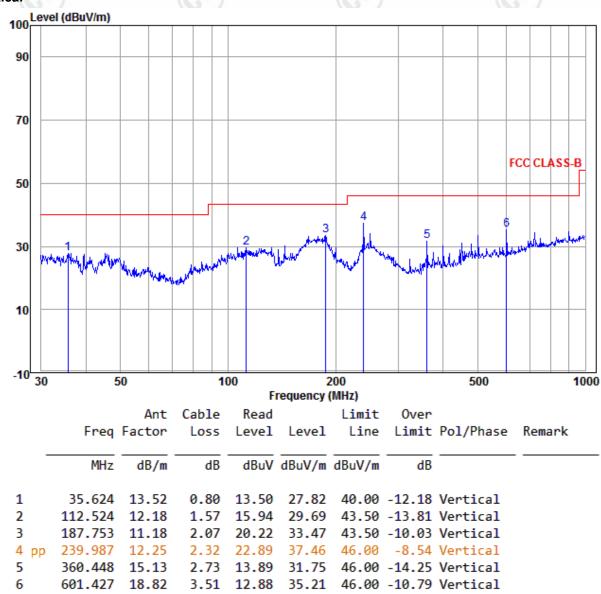








Vertical



Remark:

- The field strength is calculated by adding the Antenna Factor, Cable Factor & Preamplifier. The basic equation with a sample calculation is as follows:
 Final Test Level = Receiver Reading - Correct Factor
 - Correct Factor = Preamplifier Factor Antenna Factor Cable Factor
- 2) The highest frequency of the internal sources of the EUT is less than 108 MHz, so the measurement shall only be made up to 1 GHz.





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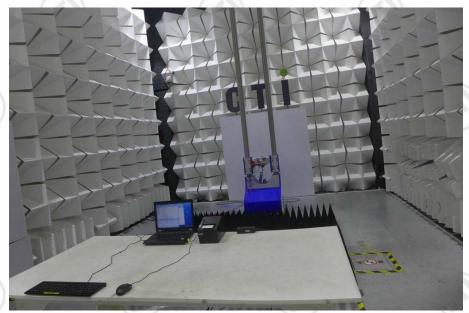


APPENDIX 1 PHOTOGRAPHS OF TEST SETUP

Test Model No.: RP80-WUS



Radiated emission Test Setup-2 (30MHz~1GHz)



Radiated spurious emission Test Setup-3(Above 1GHz)



















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Conducted Emissions



















































APPENDIX 2 PHOTOGRAPHS OF EUT

Test model No.: RP80-WUS



View of Product-1



View of Product-2







View of Product-3















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View of Product-5











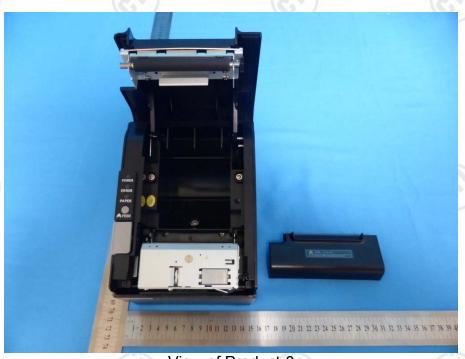




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View of Product-7



View of Product-8





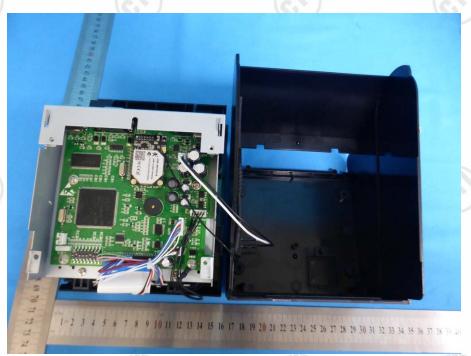








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View of Product-9



View of Product-10





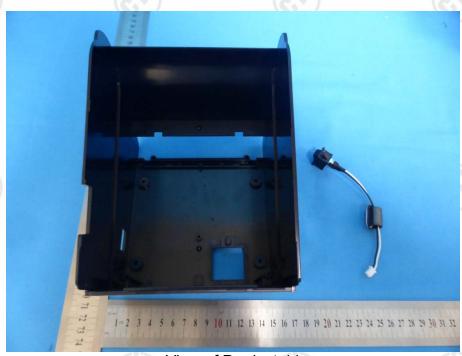








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View of Product-11







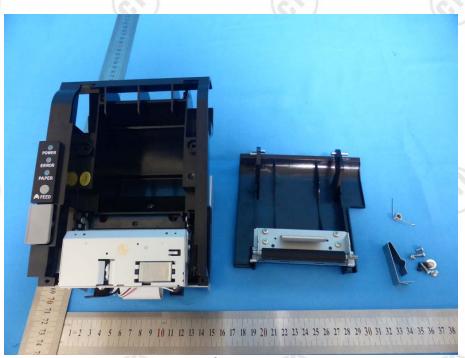








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View of Product-13



View of Product-14





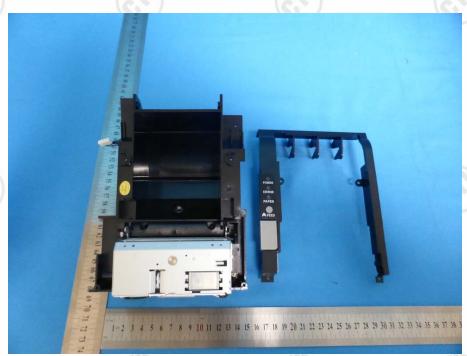




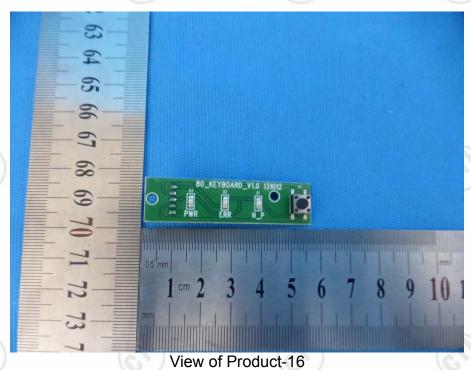








View of Product-15







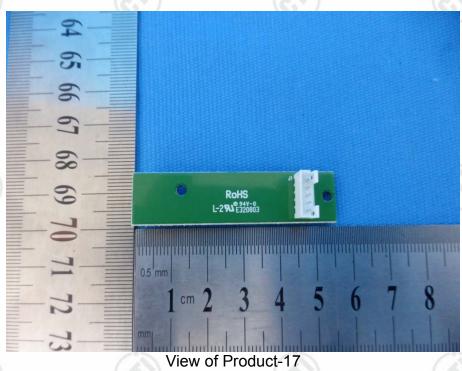








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View of Product-18









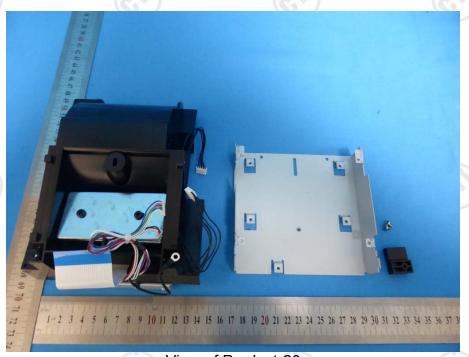




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View of Product-19



View of Product-20





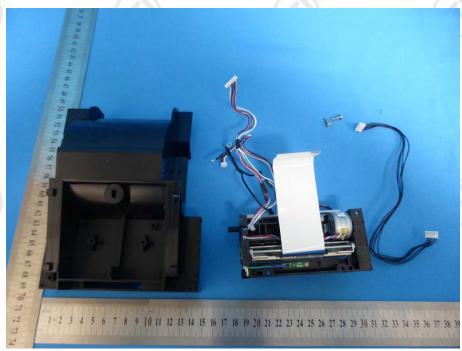








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View of Product-21



View of Product-22





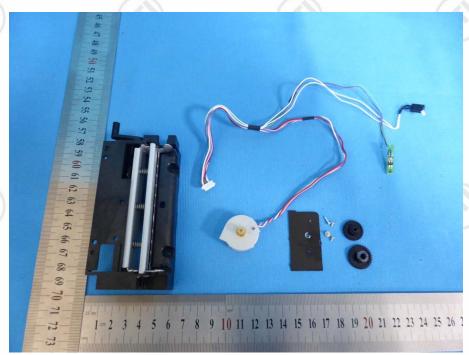




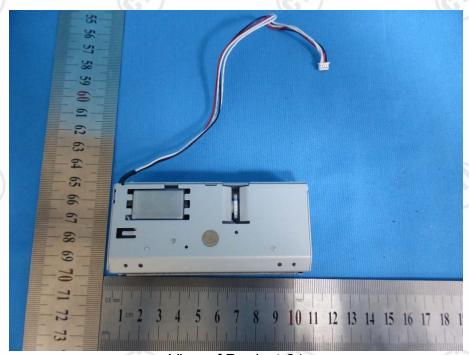




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View of Product-23



View of Product-24





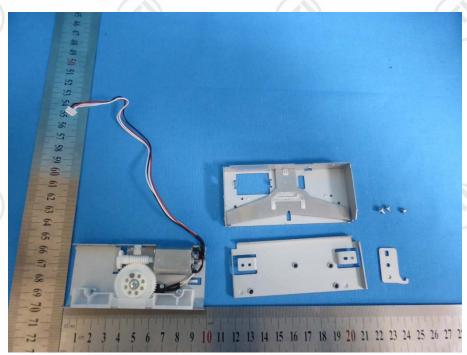




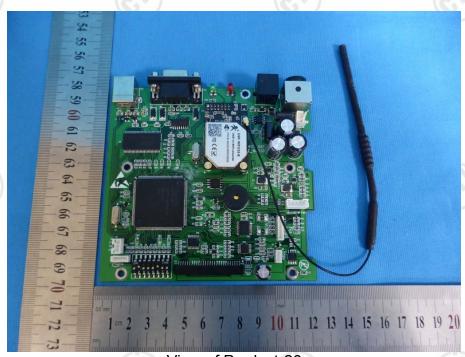




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View of Product-25



View of Product-26





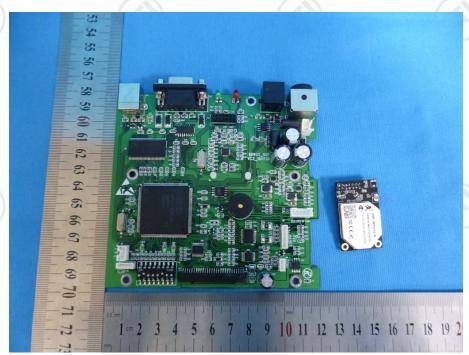




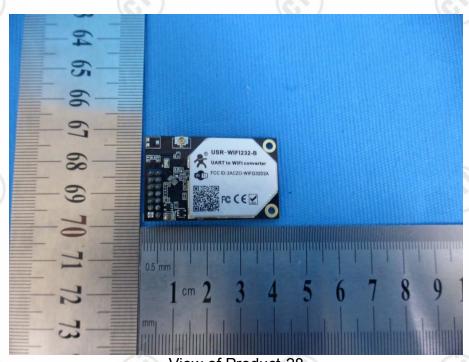




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View of Product-27



View of Product-28







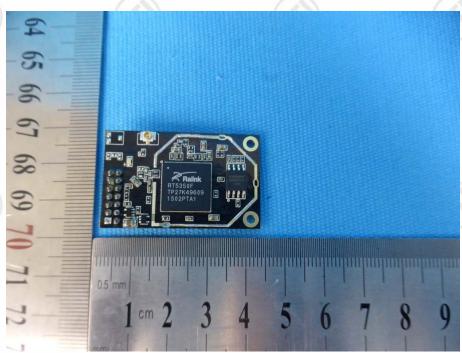




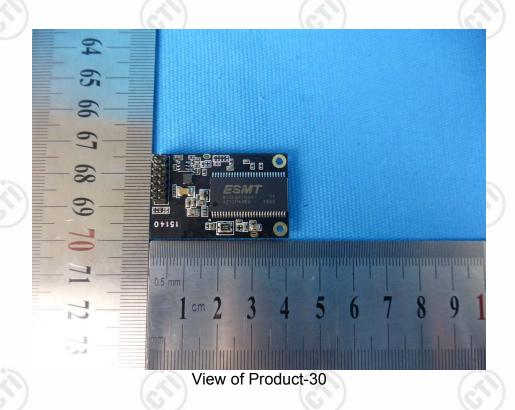




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View of Product-29











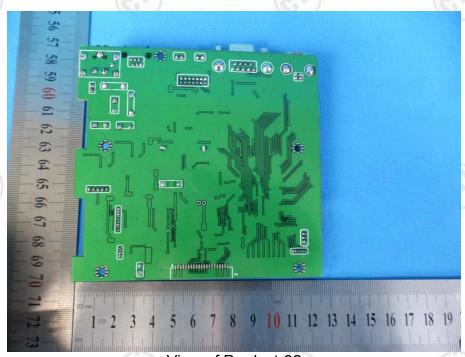




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View of Product-31



View of Product-32













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View of Product-33



View of Product-34



















View of Product-36













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View of Product-37



View of Product-38





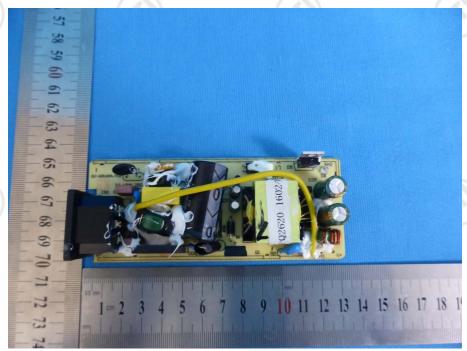




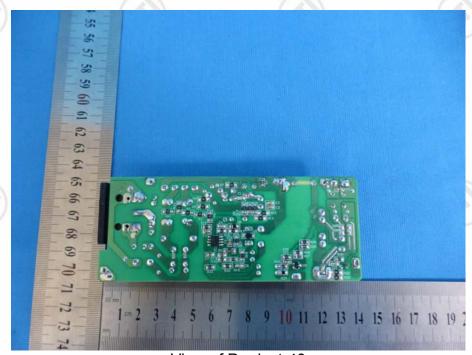




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View of Product-39



View of Product-40
*** End of Report ***

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